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High-Density Solid-State Memory Devices and Technologies

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Message from the Guest Editors

The relevance of solid-state memory technologies in the world of electronics is on the constant rise. Due to their continuously increasing integration density and their unmatched performance, solid-state memory technologies are currently not only gaining importance in the arena of data storage but are also offering the opportunity for new memory-centric computing scenarios. 3-D NAND Flash memory, phase-change memory (PCM), resistive random-access memory (MRAM), and ferroelectric memory are the most important players at the heart of this memory revolution, along with dynamic random-access memory (DRAM) and static random-access memory (SRAM).











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Message from the Editor-in-Chief

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